

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s) : Aaron PARTRIDGE et al.
Serial No. : 10/713,172
Filing Date : November 14, 2003
For : CRACK AND RESIDUE FREE CONFORMAL
DEPOSITED SILICON OXIDE WITH
PREDICTABLE AND UNIFORM ETCHING
CHARACTERISTICS
Examiner : Francis P. Smith
Group Art Unit : 4151
Confirmation No. : 9823
Customer No. : 26646

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria VA 22313-1450

I hereby certify that this correspondence is being
electronically transmitted to the United States
Patent and Trademark Office via the Office
electronic filing system on April 17, 2008

Signature: /Elizabeth Tretter/

AMENDMENT

SIR:

In response to the Office Action of January 18, 2008 (the three-month response date for is April 18, 2008), please reconsider the above-identified application based on the following.

Amendments to the Specification begin on page 2 of this paper.

Amendments to the Claims are reflected in the listing of the claims which begins on page 3 of this paper.

Remarks begin on page 11 of this paper.